

Automated design error debug using high-level decision diagrams and mutation operators

Raik, Jaan; Repinski, Urmass; Tšepurov, Anton; Hantson, Hanno; Ubar, Raimund-Johannes; Jenihhin, Maksim

Microprocessors and microsystems 2013 / p. 505-513 : ill <https://doi.org/10.1016/j.micpro.2012.11.004> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Automated design error localization in RTL designs

Jenihhin, Maksim; Tšepurov, Anton; Tihhomirov, Valentin; Raik, Jaan; Hantson, Hanno; Ubar, Raimund-Johannes;

Bartsch, Günter; Meza Escobar, Jorge Hernan; Wuttke, Heinz-Dietrich IEEE design & test of computers 2014 / p. 83-92 : ill

<https://doi.org/10.1109/MDAT.2013.2271420> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Combining dynamic slicing and mutation operators for ESL correction

Repinski, Urmass; Hantson, Hanno; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes Proceedings : 2012 17th IEEE

European Test Symposium (ETS) : May 28th-June 1st, 2012, Annecy, France 2012 / [6] p. : ill

<https://ieeexplore.ieee.org/document/6233020>

Design error repair with mutations at higher abstraction levels

Hantson, Hanno Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kuuenda aastakonverentsi artiklite kogumik : 3.-5.

oktoobril 2012, Laulasmaa 2012 / p. 21-24 : ill

Diagnosis and correction of multiple design errors using critical path tracing and mutation analysis

Hantson, Hanno; Repinski, Urmass; Raik, Jaan; Jenihhin, Maksim; Ubar, Raimund-Johannes LATW 2012 : 13th IEEE Latin-

American Test Workshop proceedings : April 10th-13th, 2012, Quito, Ecuador 2012 / [6 p.] : ill

<https://ieeexplore.ieee.org/document/6261234>

Mutation analysis for systemC designs at TLM

Guarnieri, Valerio; Bombieri, Nicola; Pravadelli, Graziano; Fummi, Franco; **Hantson, Hanno; Raik, Jaan; Jenihhin, Maksim; Ubar,**

Raimund-Johannes 12th IEEE Latin American Test Workshop (LATW) : Porto de Galinhas, Brasil, 27-30 March 2011 2011 / [6] p

<https://ieeexplore.ieee.org/document/5985925>

Mutation analysis with high-level decision diagrams

Hantson, Hanno; Raik, Jaan; Jenihhin, Maksim; Tšepurov, Anton; Ubar, Raimund-Johannes; Guglielmo, Giuseppe di;

Fummi, Franco LATW2010 : 11th Latin-American TestWorkshop, March 28-31, 2010, Punta del Este, Uruguay 2010 / [6] p. [CD-

ROM] <https://ieeexplore.ieee.org/document/5550336>

Mutation-based verification and error correction in high-level designs = Mutatsioonidel põhinev verifitseerimine ja vigade parandamine kõrgtaseme skeemides

Hantson, Hanno 2015 https://www.ester.ee/record=b4518212*est

Mutations for testing hardware and correcting design errors

Hantson, Hanno Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK viienda aastakonverentsi artiklite kogumik : 25.-26.

novembril 2011, Nelijärve 2011 / p. 105-108 : ill

On the reuse of TLM mutation analysis at RTL

Guarnieri, Valerio; **Hantson, Hanno; Raik, Jaan; Jenihhin, Maksim; Ubar, Raimund-Johannes** Journal of electronic testing :

theory and applications 2012 / p. 435-448 : ill <https://link.springer.com/article/10.1007/s10836-012-5303-6>